### Superior heat dissipation by low pressure Ag sinter joining & real time AI lifetime prediction for SiC power module



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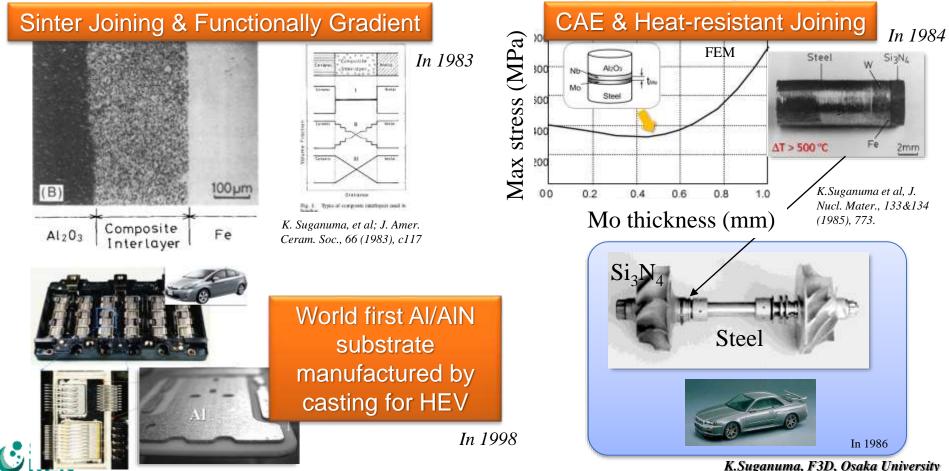
## Outline

### ✓ Introduction

- ✓ Advanced power modules & reliability
- ✓ Ag sinter joining & heat management
- ✓ Substrate and Ni-P plating
- ✓ Thermal property measurement and management
- ✓ Reliability and lifetime prediction by AE sensing + AI
- ✓ Summary



## Several contributions to ceramic/metal joining



<sup>3</sup> 

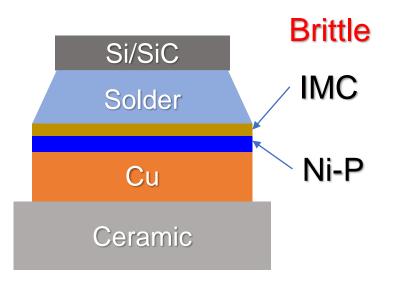
### **Towards Advanced "Tough" Semiconductors**



- Autonomous driving/flying/robot subjects require unbreakable semiconductors
- Infrastructures such as datacenter/base station require the same toughness
- These semiconductors must be monitored on their status to maintain their safe operation and the potential failure should be reported before their life-time



## Ideal interconnection



- In severe thermal cycles, IMC and Ni-P will be the origin of failure
- Brittleness of Ni-P plating should be improved
- ✓ IMC formation must be avoided
- Brittleness of ceramics must be improved

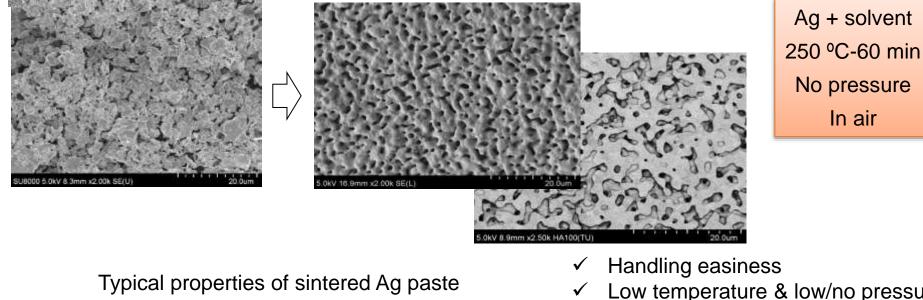


### Choices of interconnection materials

	Ostalaa	Conductive adhesive	Sinter joining	
	Solder		Nano Ag/Cu	Micron Ag/Cu
Electric conductivity	Х	Х	Ø	Ø
Thermal Conductivity	Х	Х	Ø	Ø
Strength	0	0	0	0
Heat resistance	Х	$\bigtriangleup$	Ø	Ô
IMC formation	Х	0	0	0
Cost	0	$\bigtriangleup$	X	∆/O
Others	<ul> <li>Easy handling</li> <li>~250 °C</li> </ul>	• ~150 °C	<ul><li>High pressure</li><li>200~250 °C</li></ul>	<ul><li>No/Low pressure</li><li>180~250 °C</li></ul>



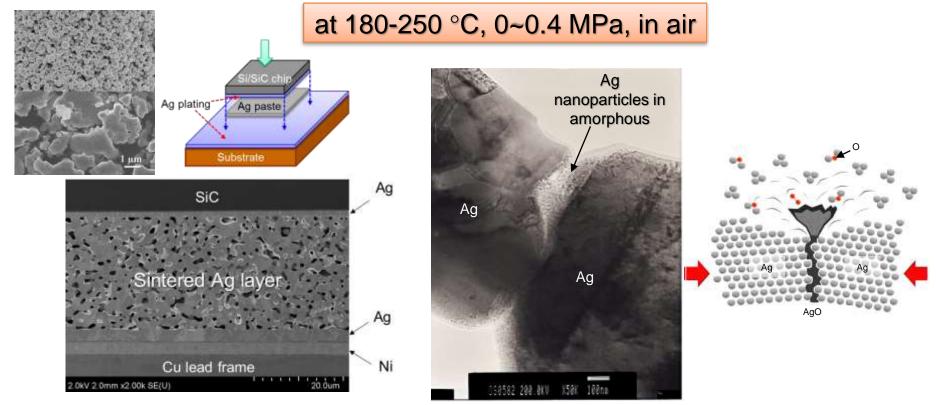
## Sintering of Ag flake pastes



Density (g/cm <sup>3</sup> )	Porosity (%)	Thermal conductivity (W/m⋅K)	
6.20	40.9	150 ~ 200	
SAN			

- Low temperature & low/no pressure
- Air atmosphere  $\checkmark$
- High performance  $\checkmark$
- Large area bonding
- Affordability

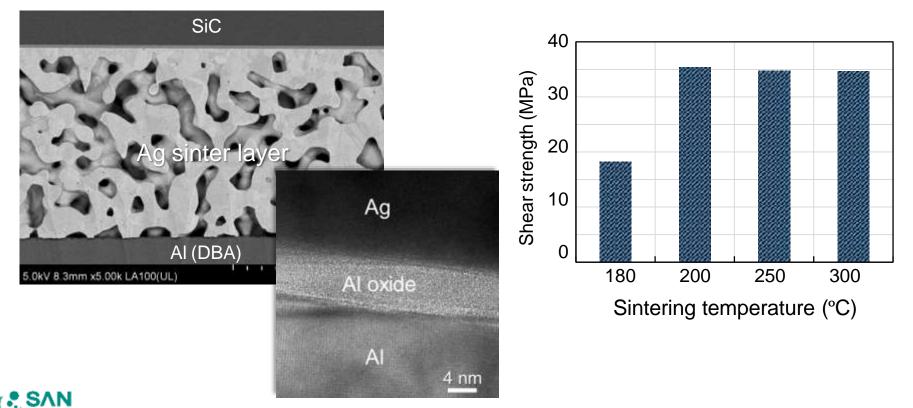
## Micron particle/film Ag joining



Suganuma et al., Microelectronics Reliability **52** (2012) 375.

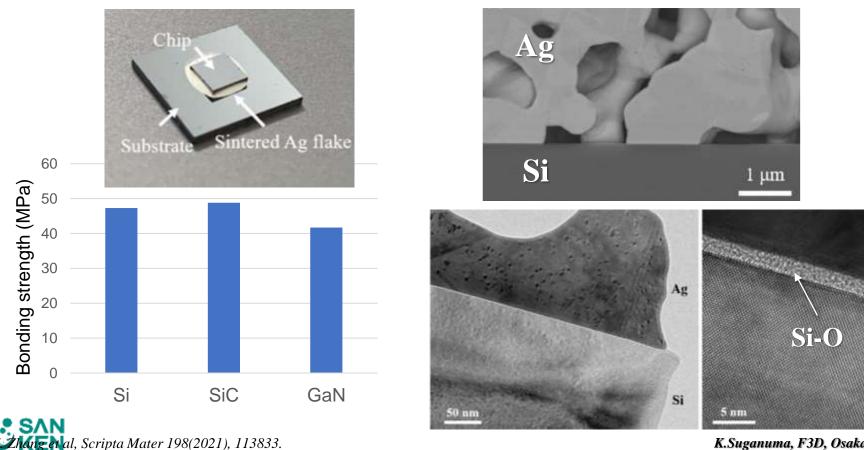
*S.-K. Lin et al, Scientific Report, 6(2016), 34769.* 

### Direct bonding without metallization



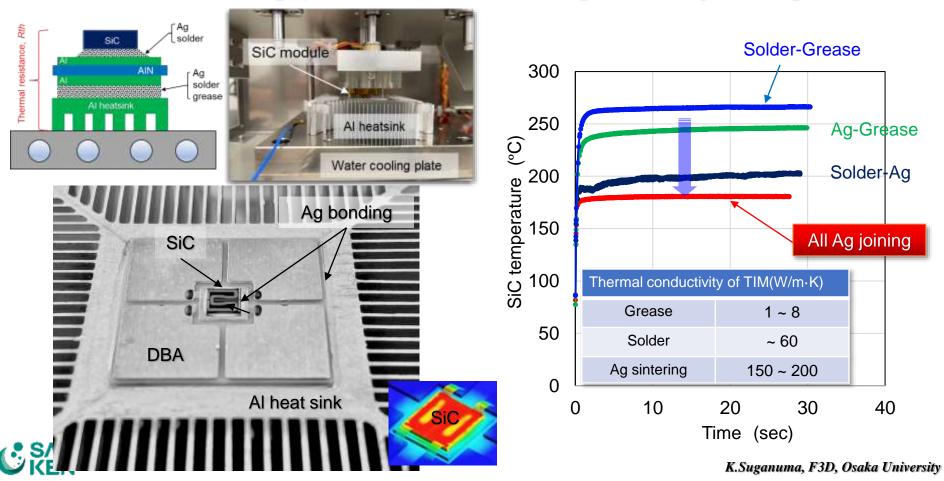
Kim et al, J. Mater. Sci. Mater. Electron., 31(2020), 587

### Direct bonding without metallization on Si/SiC/GaN



K.Suganuma, F3D, Osaka University

### Cooling performance of Ag sinter joining



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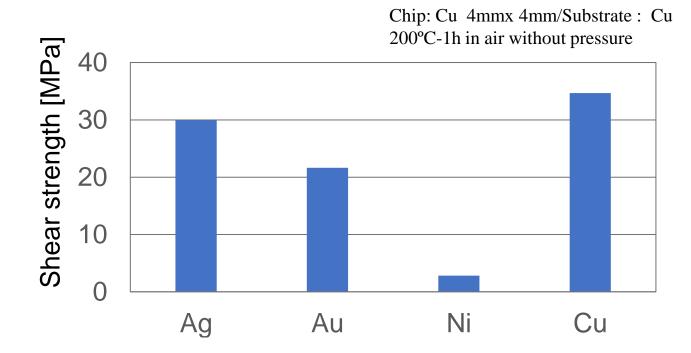
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## Bonding on various surfaces: Ag, Au, Ni, and Cu

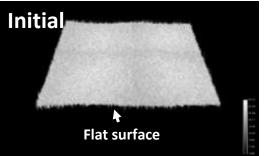


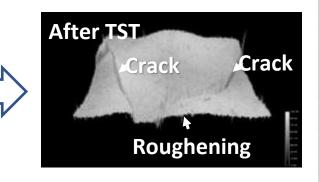


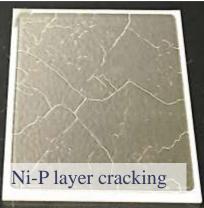
### Metal surface deformation of substrate causes serious degradation

Thermal stress causes severe deformation of metal layer on ceramic substrate resulting in Ni-P plating cracking 0 cycle Ra 1.11 100 cycle Ra 2.62 State a traditional and a state a

**Plated Ni-P surface** 

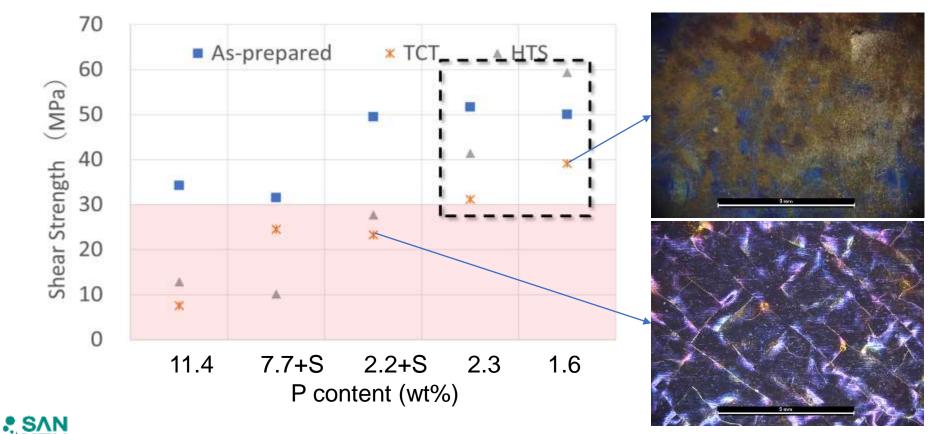








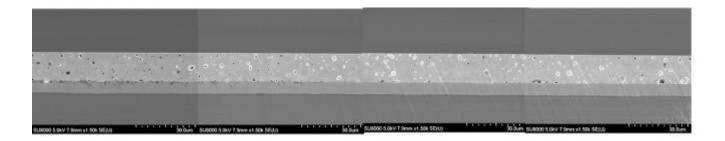
## Improvement by Ag Bonding for Ni-P plating



K.Suganuma, F3D, Osaka University

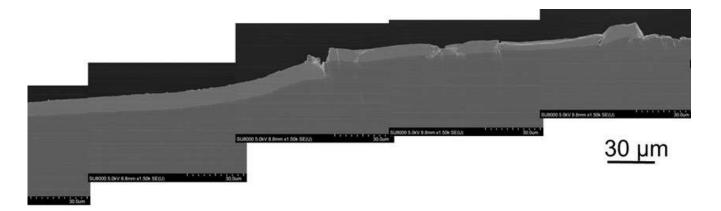
Presented at ECTC2022, in collaboration with Okuno Chemicals

### Interface after severe thermal shock test -50 °C ~ 300 °C x 500 cycles



#### Ni-1.6P

Ni-11.4P





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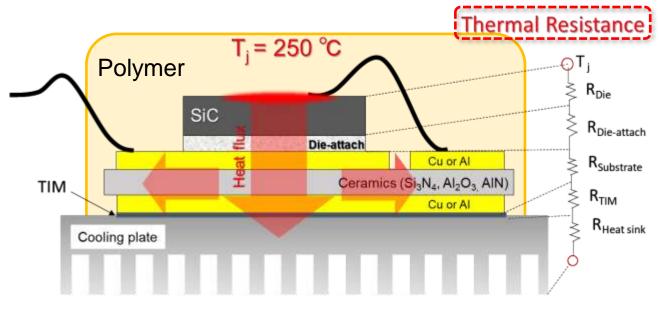
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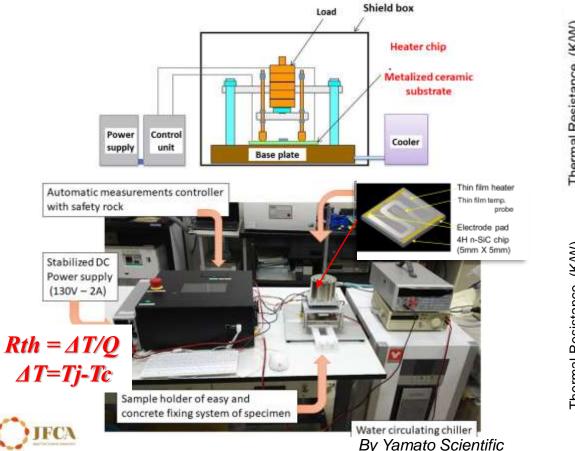
## Thermal performance evaluation/management

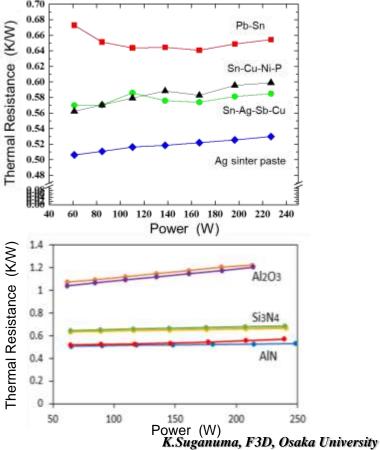


$$R_{total} = R_{die} + R_{die-attach} + R_{substrate} + R_{TIM} + R_{heat-sink}$$

We need to understand thermal dissipation performance of device structure

# ISO 4825-1:2022 Test method for thermal property measurements of metalized ceramic substrates - Part 1: Evaluation of thermal resistance for use in power modules





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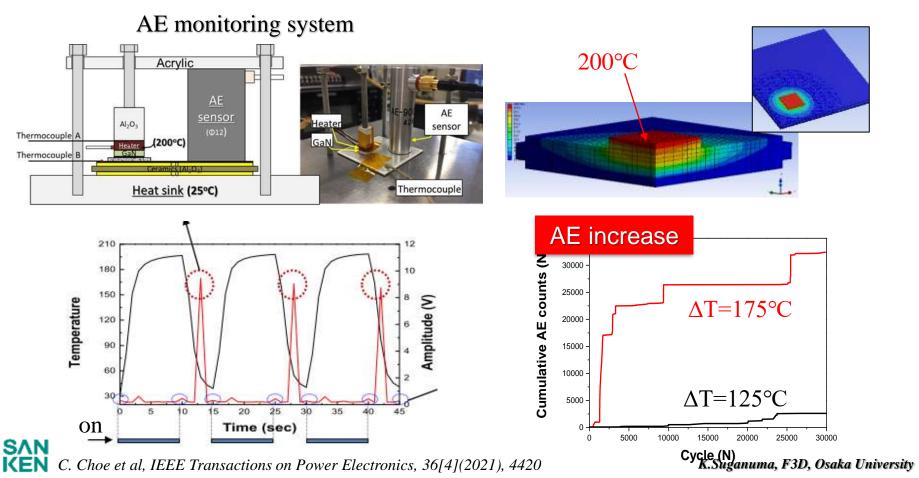
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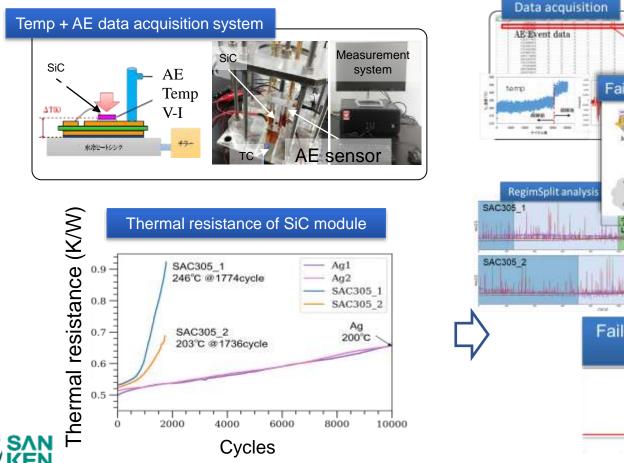


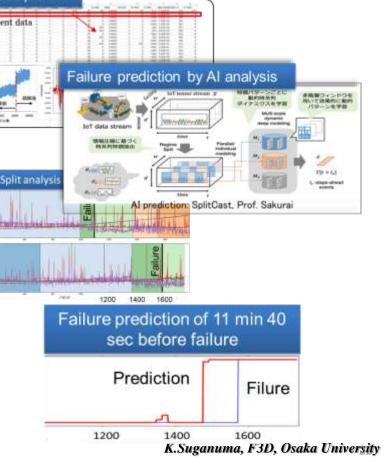
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## AE monitoring in power cycling



### AE sensing and real-time life prediction by AI technology





In collaboration with Prof. Sakurai

### Real-time AI prediction of power module failure

#### Features

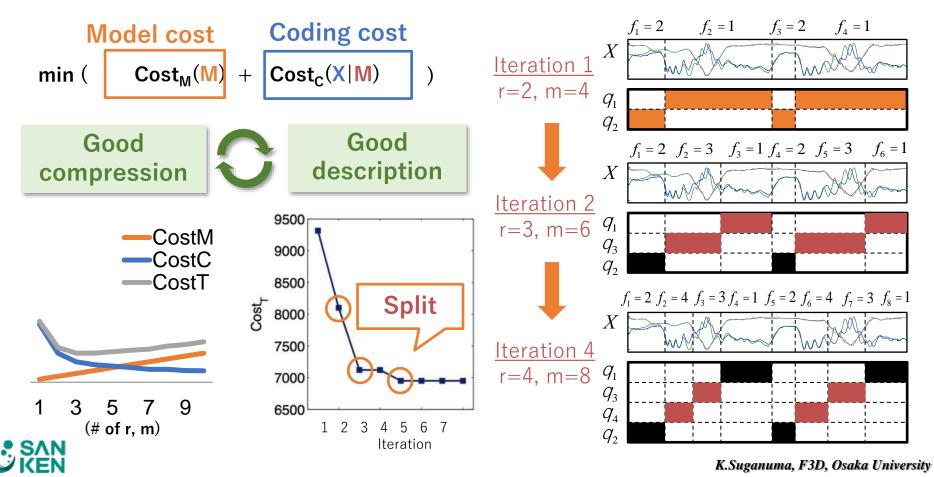
- Only one "time series" analysis in the world
- High accuracy with minimal cost compared to deep learning: 10000 faster & 10 times accuracy than others
- Real time correction/modification
- One can intuitively understand
- Effective technology for IoT-related industries such as smart factories and edges

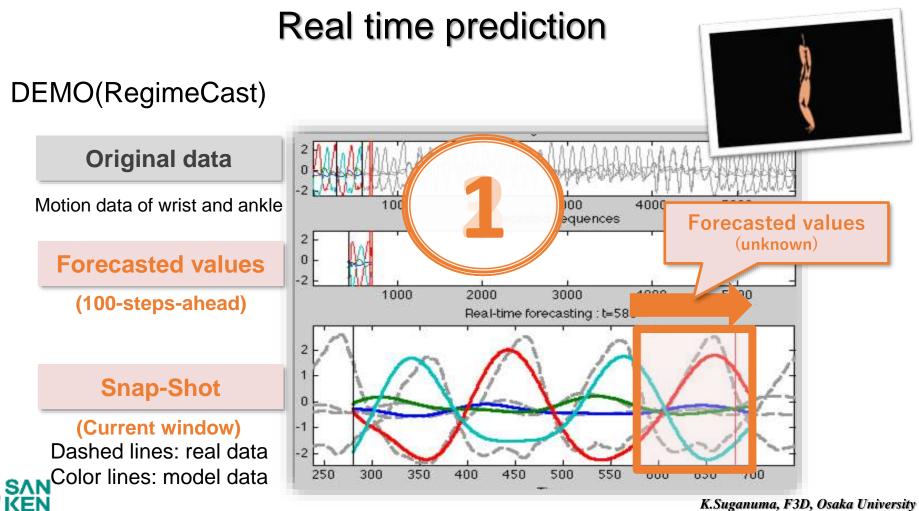




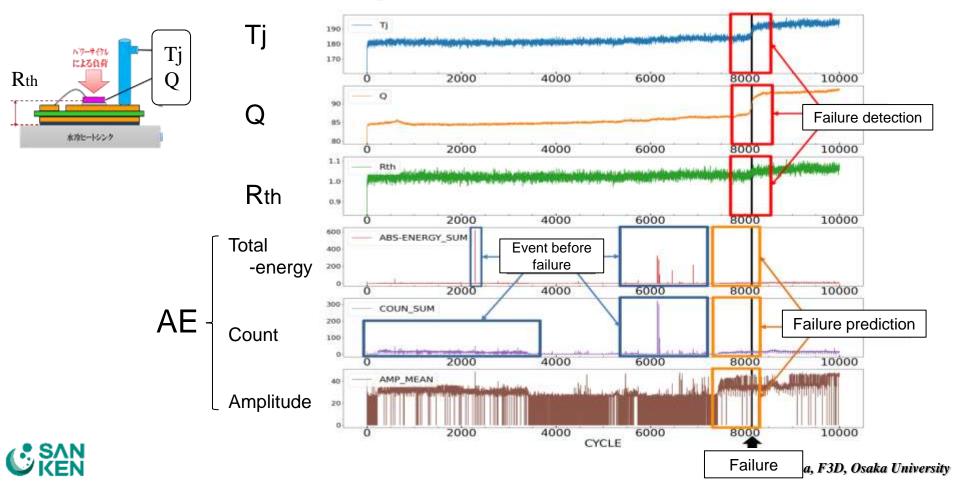
Prof. Y. Matsubara

### Self extraction of event feature

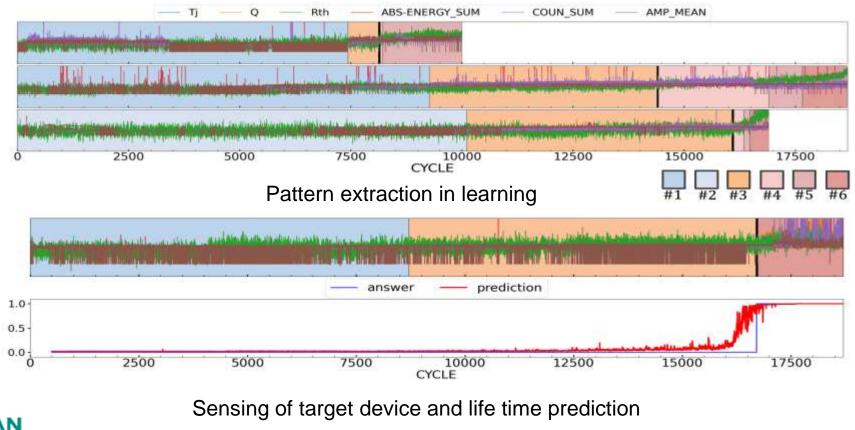




### Real sensing data from power devise



### **Failure prediction**



## Summary

- 1. Mechanism of Ag nano eruption joining is well understood.
- 2. Ag sinter joining provides high heat dissipation capability as well as high strength and stability by adjustments of process conditions and a direct Ag sinter joining becomes possible to Al/Si/SiC/GaN....etc.
- 3. Low pressure all Ag sinter joining has the great cooling performance.
- 4. New simple thermal property measurements were proposed for ISO.
- 5. AE monitoring with AI real-time prediction can provide the information on damage initiation and propagation inside package rather than Tj change.





### Questions are welcome to:

### suganuma@sanken.osaka-u.ac.jp





Acknowledgements

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